

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

4105-22

SERIAL NO.

10/658,751

APPLICANT

CHO et al.

(Use several sheets if necessary)

FILING DATE

September 10, 2003

TC/A.U.

2818

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/GP/	2007/0014047	01/2007	Cho et al.			
	2006/0219655	11/2006	Cho et al.			
	2006/0245312	11/2006	Maeda et al.			
	2006/0182004	08/2006	Maeda et al.			
	2004/0263185	12/2004	Cho et al.	324	636	
	2004/0114913	06/2004	Kume	386	125	
	2003/0053400	03/2003	Cho et al.	369	126	
	2004/0027935	02/2004	Cho et al.	369	126	
	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	
	2,872,529	02/1959	Hollmann et al.			
	4,320,491	03/1982	Rustman, James C.	369	126	
	4,455,638	06/1984	Wilson	369	126	
	4,489,278	12/1984	Sawazaki, Norikazu	324	457	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
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	5,914,920	06/1999	Yokogawa	369	275.3	
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	6,477,132	11/2002	Azuma et al.	369	126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
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	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
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	6,965,545	11/2005	Hino et al.	369	13.54	
	7,065,033	06/2006	Onoe et al.	369	126	
/GP/	7,149,180	12/2006	Onoe et al.	369	276	

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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/GP/ 2003085969	03/2003	JP			ABSTRACT
/GP/ 08-075806	03/1996	JP			ABSTRACT
/GP/ 644 426 A	10/1950	GB			
/GP/ 10-334525	12/1998	JP			ABSTRACT

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	56-107338	08/1981	JP		ABSTRACT
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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

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	2005/0098532	05/2005	Onoe et al.	216	22	
	20050047288	03/2005	Maeda et al.	369	53.25	
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	2002/0105249	08/2002	Yoshida et al.	310	311	
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	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
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	1 484 256	09/1977	GB				
	0 739 004	11/1996	EP				
/GP/	1 154 422	11/2001	EP				

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Sheet 3 of 4

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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

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